

English Version

Non-destructive Testing - Test Method for Residual Stress analysis by X-ray Diffraction

Essais non-destructifs - Méthode d'essai pour l'analyse des
contraintes résiduelles par diffraction des rayons X

Zerstörungsfreie Prüfung - Röntgendiffraktometrisches
Prüfverfahren zur Ermittlung der Eigenspannungen

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